

Notice of References Cited	Application/Control No. 10/708,153		Applicant(s)/Patent Under Reexamination LIEN ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,280,060 A	07-1981	Kure-Jensen et al.	290/40R
*	B	US-4,819,234 A	04-1989	Huber, William S.	717/129
*	C	US-5,339,422 A	08-1994	Brender et al.	714/4
*	D	US-5,548,717 A	08-1996	Wooldridge et al.	717/124
*	E	US-5,819,093 A	10-1998	Davidson et al.	717/126
*	F	US-5,819,023 A	10-1998	Klingler, Stephan	714/34
*	G	US-5,850,562 A	12-1998	Crump et al.	713/1
*	H	US-5,896,523 A	04-1999	Bissett et al.	713/400
*	I	US-6,042,614 A	03-2000	Davidson et al.	717/116
*	J	US-6,081,783 A	06-2000	Divine et al.	704/500
*	K	US-6,205,560 B1	03-2000	Hervin et al.	714/34
*	L	US-6,286,132 B1	09-2001	Tanaka et al.	717/125
*	M	US-2002/0129338 A1	09-2002	MacDonell, Kevin	717/126

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
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NON-PATENT DOCUMENTS

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	U	
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	X	

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0162051 A1	10-2002	Bolding et al.	714/34
*	B	US-6,477,666 B1	11-2002	Sanchez et al.	714/41
*	C	US-6,493,834 B1	12-2002	Bates et al.	714/38
*	D	US-6,502,102 B1	12-2002	Haswell et al.	707/102
*	E	US-2003/0005415 A1	01-2003	Bates et al.	717/129
*	F	US-2003/0041315 A1	02-2003	Bates et al.	717/129
*	G	US-2003/0037225 A1	02-2003	Deng et al.	712/227
*	H	US-2003/0037317 A1	02-2003	Emberson, David R.	717/129
*	I	US-2003/0061599 A1	03-2003	Bates et al.	717/129
*	J	US-6,543,049 B1	04-2003	Bates et al.	717/129
*	K	US-2003/0084430 A1	05-2003	Bates et al.	717/131
*	L	US-2003/0115576 A1	06-2003	Bates et al.	717/129
*	M	US-6,598,181 B1	07-2003	Pennell, Andrew M.	714/38

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0145124 A1	07-2003	GUYAN et al.	709/318
*	B	US-2003/0177476 A1	09-2003	Sarma et al.	717/128
*	C	US-2003/0188225 A1	10-2003	Bates et al.	714/38
*	D	US-2003/0208746 A1	11-2003	Bates et al.	717/129
*	E	US-6,651,187 B2	11-2003	Lacey, III, Herbert Lyvirn	714/38
*	F	US-2003/0217354 A1	11-2003	Bates et al.	717/129
*	G	US-6,658,649 B1	12-2003	Bates et al.	717/124
*	H	US-2004/0010773 A1	01-2004	Chan et al.	717/104
*	I	US-2004/0031019 A1	02-2004	Lamanna et al.	717/125
*	J	US-2005/0188358 A1	08-2005	Johnson et al.	717/129
*	K	US-6,964,035 B2	11-2005	Poynor, Todd	717/124
*	L	US-6,981,248 B2	12-2005	Bates et al.	717/129
*	M	US-6,973,417 B1	12-2005	Maxwell et al.	703/2

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,007,268 B2	02-2006	Emberson, David R.	717/127
*	B	US-7,085,700 B2	08-2006	O'Riordan et al.	703/14
*	C	US-7,133,820 B2	11-2006	Pennello et al.	703/22
*	D	US-2007/0006158 A1	01-2007	Takuma et al.	717/124
*	E	US-7,185,321 B1	02-2007	Roe et al.	717/134
*	F	US-7,206,733 B1	04-2007	Nemecek, Craig	703/25
*	G	US-7,353,427 B2	04-2008	Bates et al.	714/38
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
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	W				
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